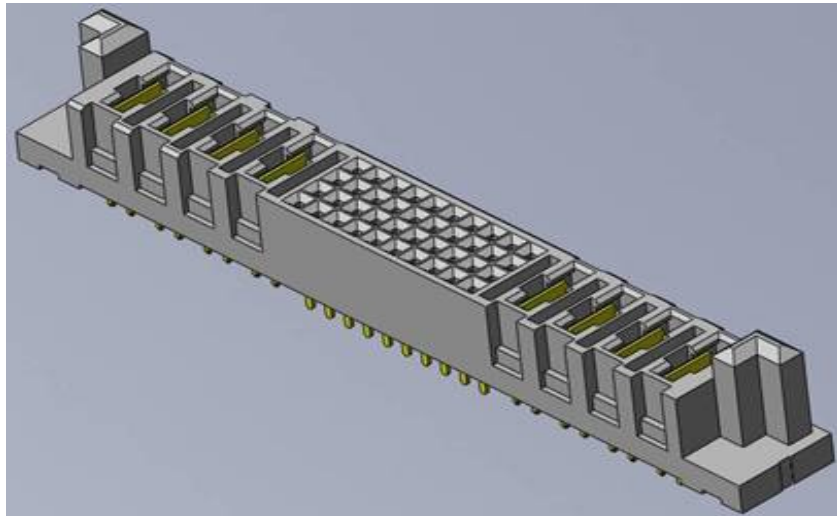
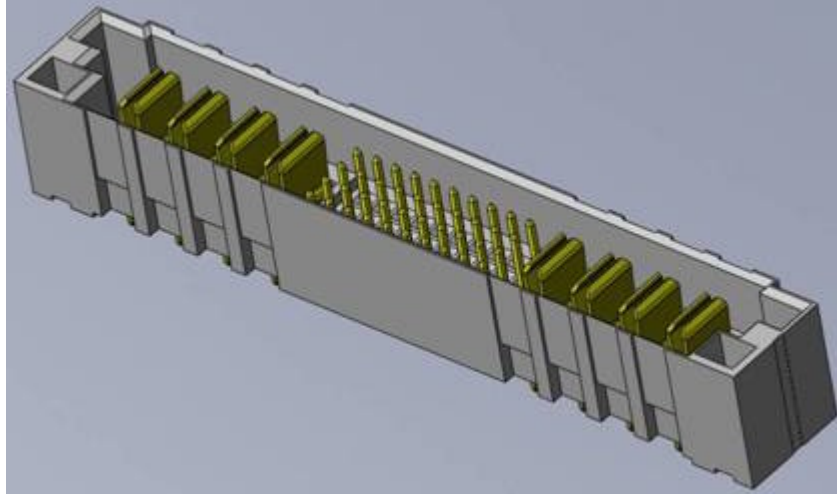




Project Number: Design Qualification Test Report		Tracking Code: 101836_Report_Rev_1	
Requested by: Adam Owens		Date: 12/3/2010	Product Rev: 0
Part #: PETC-04-40-04-01-T-VT/PESC-04-40-04-01-T-VT		Lot #: na	Tech: Troy Cook Tony Wagoner
Part description: PETC/PESC			Qty to test: 20
Test Start: 10/14/2010	Test Completed: 11/5/2010		



Design Qualification Test Report

PETC/PESC

PETC-04-40-04-01-T-VT/PESC-04-40-04-01-T-VT

CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to ISO 10012-1 and ANSI/NCSL 2540-1, as applicable.

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SCOPE

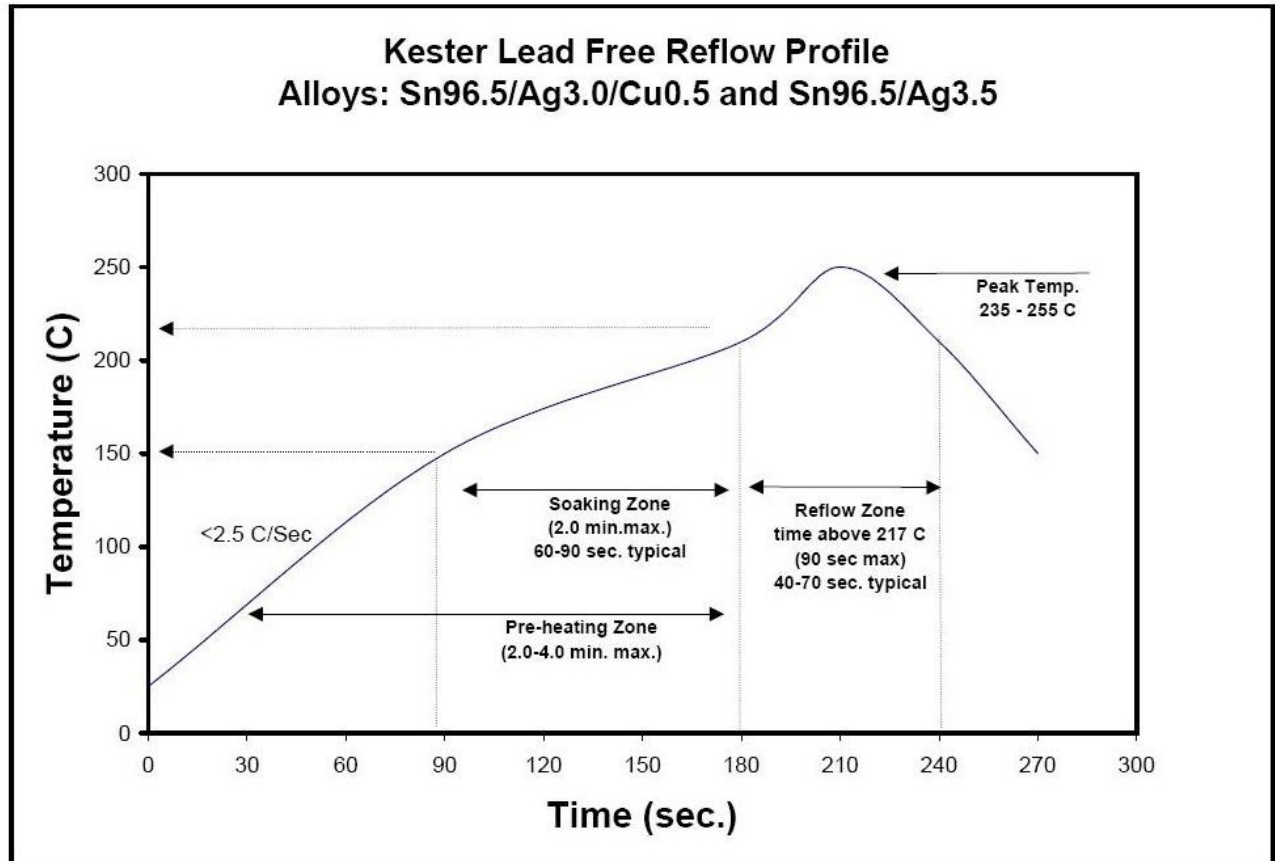
To perform the following tests: Design verification test. See test plan.

APPLICABLE DOCUMENTS

Standards: EIA Publication 364

TEST SAMPLES AND PREPARATION

- 1) All materials were manufactured in accordance with the applicable product specification.
- 2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
- 3) After soldering, the parts to be used for LLCR and DWV/IR testing were cleaned according to TLWI-0001.
- 4) Either an automated cleaning procedure or an ultrasonic cleaning procedure may be used.
- 5) The automated procedure is used with aqueous compatible soldering materials.
- 6) Parts not intended for testing LLCR and DWV/IR are visually inspected and cleaned if necessary.
- 7) Any additional preparation will be noted in the individual test sequences.
- 8) Solder Information: Lead Free
- 9) Re-Flow Time/Temp: See accompanying profile.

TYPICAL OVEN PROFILE (Soldering Parts to Test Boards)

FLOWCHARTS**IR & DWV**

TEST STEP	GROUP A1 2 Mated Sets Break Down - Pin to Pin	GROUP A2 2 Unmated of Part # Being Tested Break Down - Pin to Pin	GROUP A3 2 Unmated of Mating Part # Break Down - Pin to Pin	GROUP B 2 Mated Sets Pin to Pin
01	DWV/Break Down Voltage	DWV/Break Down Voltage	DWV/Break Down Voltage	IR & DWV at test voltage (on both mated sets and on each connector unmated)
02				Thermal Shock (both sets unmated)
03				IR & DWV at test voltage (on both mated sets and on each connector unmated)
04				Cyclic Humidity (both sets unmated)
05				IR & DWV at test voltage (on both mated sets and on each connector unmated)

* - DWV on group B to be performed at Test Voltage

DWV test voltage is equal to 75% of the lowest break down voltage from group A1, A2 or A3

Thermal Shock = EIA-364-32, Table II, Test Condition I:

-55°C to +85°C 1/2 hour dwell, 100 cycles

Humidity = EIA-364-31, Test Condition B (240 Hours)

and Method III (+25° C to +65° C @ 90%RH to 98% RH)

ambient pre-condition and delete steps 7a and 7b

IR = EIA-364-21. Greater than 5000 Meg Ohms

DWV = EIA-364-20, Test at 75 % of the minimum breakdown voltage of the connector

FLOWCHARTS CONTINUED**IR & DWV**

TEST STEP	GROUP A1 2 Mated Sets Break Down - Pin to Ground	GROUP A2 2 Unmated of Part # Being Tested Break Down - Pin to Ground	GROUP A3 2 Unmated of Mating Part # Break Down - Pin to Ground	GROUP B 2 Mated Sets Pin to Ground
01	DWV/Break Down Voltage	DWV/Break Down Voltage	DWV/Break Down Voltage	IR & DWV at test voltage (on both mated sets and on each connector unmated)
02				Thermal Shock (both sets unmated)
03				IR & DWV at test voltage (on both mated sets and on each connector unmated)
04				Cyclic Humidity (both sets unmated)
05				IR & DWV at test voltage (on both mated sets and on each connector unmated)

* - DWV on group B to be performed at Test Voltage

DWV test voltage is equal to 75% of the lowest break down voltage from group A1, A2 or A3

Thermal Shock = EIA-364-32, Table II, Test Condition I:

-55°C to +85°C 1/2 hour dwell, 100 cycles

Humidity = EIA-364-31, Test Condition B (240 Hours)

and Method III (+25° C to +65° C @ 90%RH to 98% RH)

ambient pre-condition and delete steps 7a and 7b

IR = EIA-364-21. Greater than 5000 Meg Ohms

DWV = EIA-364-20, Test at 75 % of the minimum breakdown voltage of the connector

FLOWCHARTS CONTINUED**IR & DWV**

TEST STEP	GROUP A1 2 Mated Sets Break Down - Row to Row	GROUP A2 2 Unmated of Part # Being Tested Break Down - Row to Row	GROUP A3 2 Unmated of Mating Part # Break Down - Row to Row	GROUP B 2 Mated Sets Row to Row
01	DWV/Break Down Voltage	DWV/Break Down Voltage	DWV/Break Down Voltage	IR & DWV at test voltage (on both mated sets and on each connector unmated)
02				Thermal Shock (both sets unmated)
03				IR & DWV at test voltage (on both mated sets and on each connector unmated)
04				Cyclic Humidity (both sets unmated)
05				IR & DWV at test voltage (on both mated sets and on each connector unmated)

* - DWV on group B to be performed at Test Voltage

DWV test voltage is equal to 75% of the lowest break down voltage from group A1, A2 or A3

Thermal Shock = EIA-364-32, Table II, Test Condition I:

-55°C to +85°C 1/2 hour dwell, 100 cycles

Humidity = EIA-364-31, Test Condition B (240 Hours)

and Method III (+25° C to +65° C @ 90%RH to 98% RH)

ambient pre-condition and delete steps 7a and 7b

IR = EIA-364-21. Greater than 5000 Meg Ohms

DWV = EIA-364-20, Test at 75 % of the minimum breakdown voltage of the connector

ATTRIBUTE DEFINITIONS

The following is a brief, simplified description of attributes.

HUMIDITY:

- 1) Reference document: EIA-364-31, *Humidity Test Procedure for Electrical Connectors*.
- 2) Test Condition B, 240 Hours.
- 3) Method III, +25° C to + 65° C, 90% to 98% Relative Humidity excluding sub-cycles 7a and 7b.
- 4) All samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

THERMAL SHOCK:

- 1) EIA-364-32, *Thermal Shock (Temperature Cycling) Test Procedure for Electrical Connectors*.
- 2) Test Condition 1: -55°C to +85°C
- 3) Test Time: ½ hour dwell at each temperature extreme
- 4) Number of Cycles: 100
- 5) All test samples are pre-conditioned at ambient.
- 6) All test samples are exposed to environmental stressing in the mated condition.

INSULATION RESISTANCE (IR):

To determine the resistance of insulation materials to leakage of current through or on the surface of these materials when a DC potential is applied.

- 1) PROCEDURE:
 - a. Reference document: EIA-364-21, *Insulation Resistance Test Procedure for Electrical Connectors*.
 - b. Test Conditions:
 - i. Between Adjacent Contacts or Signal-to-Ground
 - ii. Electrification Time 2.0 minutes
 - iii. Test Voltage (500 VDC) corresponds to calibration settings for measuring resistances.
- 2) MEASUREMENTS:
- 3) When the specified test voltage is applied (VDC), the insulation resistance shall not be less than 5000 megohms.

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

To determine if the sockets can operate at its rated voltage and withstand momentary over potentials due to switching, surges, and other similar phenomenon. Separate samples are used to evaluate the effect of environmental stresses so not to influence the readings from arcing that occurs during the measurement process.

- 1) PROCEDURE:
 - a. Reference document: EIA-364-20, *Withstanding Voltage Test Procedure for Electrical Connectors*.
 - b. Test Conditions:
 - i. Between Adjacent Contacts or Signal-to-Ground
 - ii. Barometric Test Condition 1
 - iii. Rate of Application 500 V/Sec
 - iv. Test Voltage (VAC) until breakdown occurs
- 2) MEASUREMENTS/CALCULATIONS
 - a. The breakdown voltage shall be measured and recorded.
 - b. The dielectric withstanding voltage shall be recorded as 75% of the minimum breakdown voltage.
 - c. The working voltage shall be recorded as one-third (1/3) of the dielectric withstanding voltage (one-fourth of the breakdown voltage).

RESULTS**Insulation Resistance minimums, IR****Pin to Pin**

- **Initial**
 - Mated ----- 10000Meg Ω ----- Pass
 - Unmated----- 10000Meg Ω ----- Pass
- **Thermal**
 - Mated ----- 25000Meg Ω ----- Pass
 - Unmated----- 50000Meg Ω ----- Pass
- **Humidity**
 - Mated ----- 25000Meg Ω ----- Pass
 - Unmated----- 50000Meg Ω ----- Pass

Pin to Ground

- **Initial**
 - Mated ----- 10000Meg Ω ----- Pass
 - Unmated----- 10000Meg Ω ----- Pass
- **Thermal**
 - Mated ----- 15000Meg Ω ----- Pass
 - Unmated----- 15000Meg Ω ----- Pass
- **Humidity**
 - Mated ----- 10000Meg Ω ----- Pass
 - Unmated----- 10000Meg Ω ----- Pass

Row to Row

- **Initial**
 - Mated ----- 10000Meg Ω ----- Pass
 - Unmated----- 10000Meg Ω ----- Pass
- **Thermal**
 - Mated ----- 10000Meg Ω ----- Pass
 - Unmated----- 10000Meg Ω ----- Pass
- **Humidity**
 - Mated ----- 10000Meg Ω ----- Pass
 - Unmated----- 50000Meg Ω ----- Pass

RESULTS CONTINUED**Dielectric Withstanding Voltage minimums, DWV****Pin to Pin**• **Minimums**

- Breakdown Voltage ----- 2200 VAC
- Test Voltage ----- 1650 VAC
- Working Voltage ----- 550 VAC

Pin to Ground• **Minimums**

- Breakdown Voltage ----- 2500 VAC
- Test Voltage ----- 1875 VAC
- Working Voltage ----- 625 VAC

Row to Row• **Minimums**

- Breakdown Voltage ----- 1800 VAC
- Test Voltage ----- 1350 VAC
- Working Voltage ----- 450 VAC

Pin to Pin

- Initial DWV ----- Passed
- Thermal DWV ----- Passed
- Humidity DWV ----- Passed

Pin to Ground

- Initial DWV ----- Passed
- Thermal DWV ----- Passed
- Humidity DWV ----- Passed

Row to Row

- Initial DWV ----- Passed
- Thermal DWV ----- Passed
- Humidity DWV ----- Passed

DATA SUMMARIES**INSULATION RESISTANCE (IR):**

Pin to Pin			
	Mated	Unmated	Unmated
Minimum	PETC/PESC	PETC	PESC
Initial	100000	100000	100000
Thermal	25000	100000	50000
Humidity	25000	50000	100000
Pin to Ground			
	Mated	Unmated	Unmated
Minimum	PETC/PESC	PETC	PESC
Initial	100000	100000	100000
Thermal	15000	100000	15000
Humidity	100000	100000	100000
Row to Row			
	Mated	Unmated	Unmated
Minimum	PETC/PESC	PETC	PESC
Initial	100000	100000	100000
Thermal	100000	100000	100000
Humidity	100000	50000	100000

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

Voltage Rating Summary	
Minimum	PETC/PESC
Break Down Voltage	1800
Test Voltage	1350
Working Voltage	450
Pin to Pin	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed
Row to Row	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed
Pin to Ground	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed

DATA**INSULATION RESISTANCE (IR):**

Initial Insulation Resistance	
Measured In Meg Ohms	

Pin to Pin			
	Mated	A Unmated	B
	X	X	X
Sample#	PETC/PESC	PETC	PESC
101836-005	100000	100000	100000
101836-006	100000	100000	100000

Pin to Ground			
	Mated	A Unmated	B
	X	X	X
Sample#	PETC/PESC	PETC	PESC
101836-005	100000	100000	100000
101836-006	100000	100000	100000

Row to Row			
	Mated	A Unmated	B
	X	X	X
Sample#	PETC/PESC	PETC	PESC
101836-005	100000	100000	100000
101836-006	100000	100000	100000

DATA CONTINUED**Thermal Insulation Resistance**

Measured In Meg Ohms

Pin to Pin			
	Mated	A	Unmated B
	X	X	X
Sample#	PETC/PESC	PETC	PESC
101836-005	25000	100000	50000
101836-006	100000	100000	100000

Pin to Ground			
	Mated	A	Unmated B
	X	X	X
Sample#	PETC/PESC	PETC	PESC
101836-005	15000	100000	25000
101836-006	25000	100000	15000

Row to Row			
	Mated	A	Unmated B
	X	X	X
Sample#	PETC/PESC	PETC	PESC
101836-005	100000	100000	100000
101836-006	100000	100000	100000

DATA CONTINUED**Humidity Insulation Resistance**

Measured In Meg Ohms

Pin to Pin			
	Mated	A	Unmated B
	X	X	X
Sample#	PETC/PESC	PETC	PESC
101836-005	100000	100000	100000
101836-006	25000	50000	100000

Pin to Ground			
	Mated	A	Unmated B
	X	X	X
Sample#	PETC/PESC	PETC	PESC
101836-005	100000	100000	100000
101836-006	100000	100000	100000

Row to Row			
	Mated	A	Unmated B
	X	X	X
Sample#	PETC/PESC	PETC	PESC
101836-005	100000	50000	100000
101836-006	100000	100000	100000

DATA CONTINUED**DIELECTRIC WITHSTANDING VOLTAGE (DWV):**

Initial Breakdown Voltage	
Test Voltage <i>Until Breakdown Occurs</i>	

Pin to Pin			
Mated		A	Unmated B
X			
Sample#	PETC/PESC	PETC	PESC
101836-001	2500	2300	2200
101836-002	2300	2600	2500

Pin to Ground			
Mated		A	Unmated B
X			
Sample#	PETC/PESC	PETC	PESC
101836-001	2800	3000	3200
101836-002	3000	3300	2500

Row to Row			
Mated		A	Unmated B
X			
Sample#	PETC/PESC	PETC	PESC
101836-001	1900	1900	2000
101836-002	1800	1800	2100

DATA CONTINUED**Initial DWV****Test Voltage= 1350****Pin to Pin**

Sample#	Mated	A	Unmated	B
	PETC/PESC	PETC	PESC	PESC
101836-005	1350	1350	1350	1350
101836-006	1350	1350	1350	1350

Pin to Ground

Sample#	Mated	A	Unmated	B
	PETC/PESC	PETC	PESC	PESC
101836-005	1350	1350	1350	1350
101836-006	1350	1350	1350	1350

Row to Row

Sample#	Mated	A	Unmated	B
	PETC/PESC	PETC	PESC	PESC
101836-005	1350	1350	1350	1350
101836-006	1350	1350	1350	1350

DATA CONTINUED**Thermal Test Voltage****Test Voltage=1350****Pin to Pin**

Sample#	Mated	A	Unmated	B
	PETC/PESC	PETC	PESC	PESC
101836-005	1350	1350	1350	1350
101836-006	1350	1350	1350	1350

Pin to Ground

Sample#	Mated	A	Unmated	B
	PETC/PESC	PETC	PESC	PESC
101836-005	1350	1350	1350	1350
101836-006	1350	1350	1350	1350

Row to Row

Sample#	Mated	A	Unmated	B
	PETC/PESC	PETC	PESC	PESC
101836-005	1350	1350	1350	1350
101836-006	1350	1350	1350	1350

DATA CONTINUED**Humidity Test Voltage**

Test Voltage=1350

Pin to Pin			
	Mated	A	Unmated B
Sample#	PETC/PESC	PETC	PESC
101836-005	1350	1350	1350
101836-006	1350	1350	1350

Pin to Ground			
	Mated	A	Unmated B
Sample#	PETC/PESC	PETC	PESC
101836-005	1350	1350	1350
101836-006	1350	1350	1350

Row to Row			
	Mated	A	Unmated B
Sample#	PETC/PESC	PETC	PESC
101836-005	1350	1350	1350
101836-006	1350	1350	1350

EQUIPMENT AND CALIBRATION SCHEDULES**Equipment #:** TSC-01**Description:** Vertical Thermal Shock Chamber**Manufacturer:** Cincinnatti Sub Zero**Model:** VTS-3-6-6-SC/AC**Serial #:** 10-VT14993**Accuracy:** See Manual

... Last Cal: 05/18/2010, Next Cal: 05/18/2011

Equipment #: THC-01**Description:** Temperature/Humidity Chamber**Manufacturer:** Thermotron**Model:** SM-8-7800**Serial #:** 30676**Accuracy:** See Manual

... Last Cal: 08/16/2010, Next Cal: 02/16/2011

Equipment #: HPM-01**Description:** Hipot Megommeter**Manufacturer:** Hipotronics**Model:** H306B-A**Serial #:** M9905004**Accuracy:** 2 % Full Scale Accuracy

... Last Cal: 11/30/2009, Next Cal: 11/30/2010